SN74CBTLV3257 LOW-VOLTAGE 4-BIT 1-OF-2 FET MULTIPLEXER/DEMULTIPLEXER

SCDS040C - DECEMBER 1997 - REVISED OCTOBER 1998

- Functionally Equivalent to QS3257
- 5-Ω Switch Connection Between Two Ports
- Isolation Under Power-Off Conditions
- Package Options Include Thin Very Small-Outline (DGV), Small-Outline (DW), and Thin Shrink Small-Outline (PW) Packages

(TOP VIEW) 16**[]** V_{CC} S 1В1 П 15 1 OE 1B2 **∏**3 14**∏** 4B1 13**∏** 4B2 1A 2B1 12**| 1** 4A 2B2 **[**]6 11 **[**] 3B1 10 3B2 2A 🛮 7 9**∏** 3A GND

DGV, DW, OR PW PACKAGE

description

The SN74CBTLV3257 is a 4-bit 1-of-2 high-speed FET multiplexer/demultiplexer. The low on-state resistance of the switch allows connections to be made with minimal propagation delay.

The select (S) input controls the data flow. The FET multiplexers/demultiplexers are disabled when the output-enable (\overline{OE}) input is high.

To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN74CBTLV3257 is characterized for operation from -40°C to 85°C.

FUNCTION TABLE

INPU	JTS	FUNCTION			
ŌĒ	S	FUNCTION			
L	L	A port = B1 port			
L	Н	A port = B2 port			
Н	Χ	Disconnect			

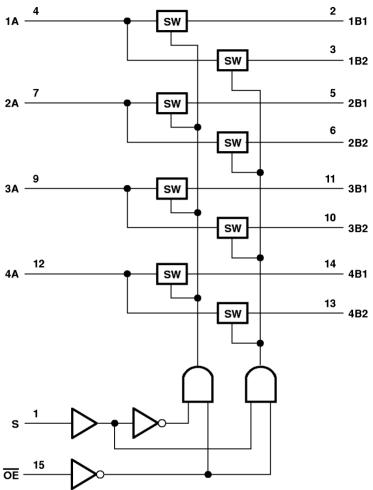


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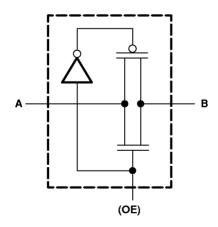


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logic diagram (positive logic)



simplified schematic, each FET switch



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC}		-0.5 V to 4.6 V
Input voltage range, V _I (see Note 1)		-0.5 V to 4.6 V
Continuous channel current		128 mA
Input clamp current, I_{IK} ($V_{I/O} < 0$)		–50 mA
Package thermal impedance, θ _{JA} (see Note 2)	: DGV package	180°C/W
	DW package	105°C/W
	PW package	149°C/W
Storage temperature range, T _{stg}		65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions (see Note 3)

			MIN	MAX	UNIT
V _{CC} Supply voltage			2.3	3.6	V
VIH	High lavel control in a strollar o	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	1.7		V
	High-level control input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		】
	Law layed control input valtage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$	0.7		V
V_{IL}	Low-level control input voltage	$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$		0.8	V
TA	Operating free-air temperature		-4 0	85	°C

NOTE 3: All unused control inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PAR	AMETER	TEST CONDITIONS		MIN	TYP‡	MAX	UNIT	
VIK		V _{CC} = 3 V,	I _I = -18 mA				-1.2	٧
Тį		$V_{CC} = 3.6 \text{ V},$	$V_I = V_{CC}$ or GND				±1	μΑ
loff		$V_{CC} = 0$,	$V_{ }$ or $V_{ } = 0$ to 4.5 V	,			10	μΑ
Icc		$V_{CC} = 3.6 \text{ V},$	I _O = 0,	V _I = V _{CC} or GND			10	μΑ
ΔI _{CC} §	Control inputs	V _{CC} = 3.6 V,	One input at 3 V,	Other inputs at V _{CC} or GND			300	μΑ
Ci	Control inputs	V _I = 3 V or 0						pF
0	A port		OE = V _{CC}					
C _{io} (OFF)	B port	$V_O = 3 \text{ V or } 0,$						pF
	-		V. 0	I _I = 64 mA				
		V _{CC} = 2.3 V, TYP at V _{CC} = 2.5 V	V _I = 0	I _I = 24 mA				
r _{on} ¶		1111 41 400 = 2.5 4	$V_{ } = 1.7 V$	I _I = 15 mA				Ω
on"		VCC = 3 V	V _I = 0	I _I = 64 mA				22
				I _I = 24 mA				
			V ₁ = 2.4 V,	l _I = 15 mA				

[‡] All typical values are at V_{CC} = 3.3 V (unless otherwise noted), T_A = 25°C.



NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.

^{2.} The package thermal impedance is calculated in accordance with JESD 51.

[§] This is the increase in supply current for each input that is at the specified voltage level rather than V_{CC} or GND.

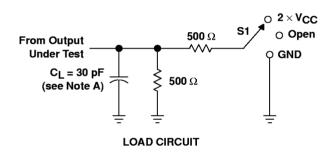
[¶] Measured by the voltage drop between the A and the B terminals at the indicated current through the switch. On-state resistance is determined by the lower of the voltages of the two (A or B) terminals.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 and 2)

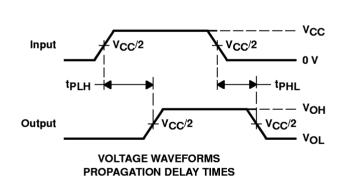
PARAMETER	FROM (INPUT)	ТО (ОИТРИТ)	V _{CC} = 2.5 V ± 0.2 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
	(INPOT)		MIN	MAX	MIN	MAX	
	A or B†	B or A					
^t pd	S	A or B					ns
t _{en}	S	A or B					ns
^t dis	S	A or B					ns
t _{en}	ŌĒ	A or B					ns
^t dis	Œ	A or B					ns

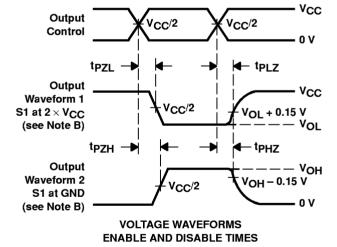
[†] The propagation delay is the calculated RC time constant of the typical on-state resistance of the switch and the specified load capacitance, when driven by an ideal voltage source (zero output impedance).

PARAMETER MEASUREMENT INFORMATION $V_{CC} = 2.5 V \pm 0.2 V$



TEST	S1		
t _{pd}	Open		
tpLZ/tpZL	2×V _{CC}		
tPHZ/tPZH	GND		





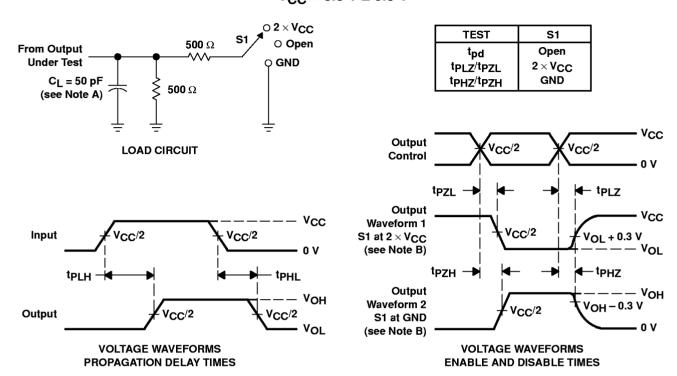
NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_O = 50 \ \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tpLZ and tpHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tplH and tpHL are the same as tpd.

Figure 1. Load Circuit and Voltage Waveforms



PARAMETER MEASUREMENT INFORMATION $V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, $Z_Q = 50 \Omega$, $t_f \leq$ 2 ns, $t_f \leq$ 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.
 - E. tpLz and tpHz are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpl H and tpHI are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms

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